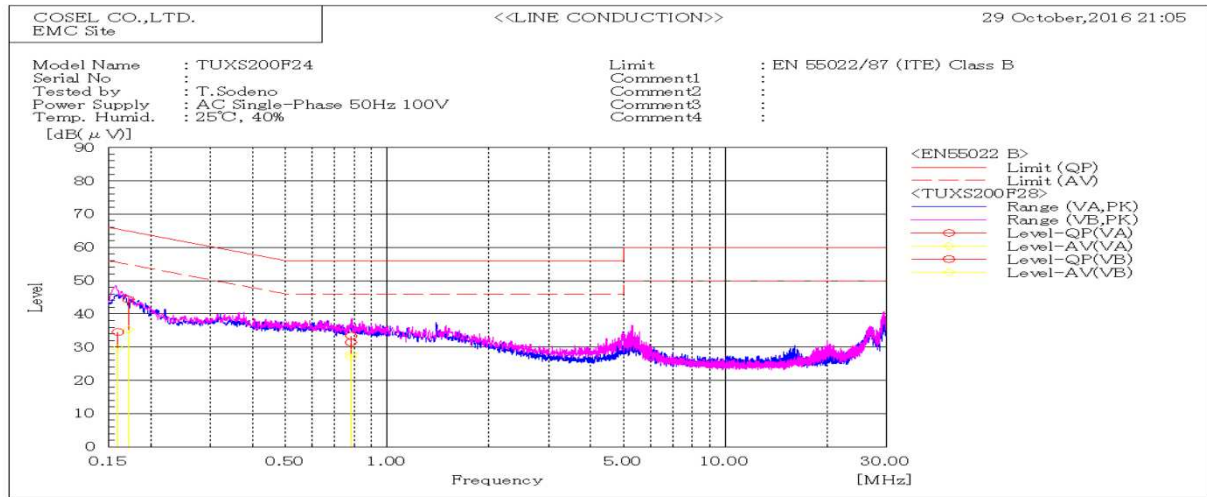
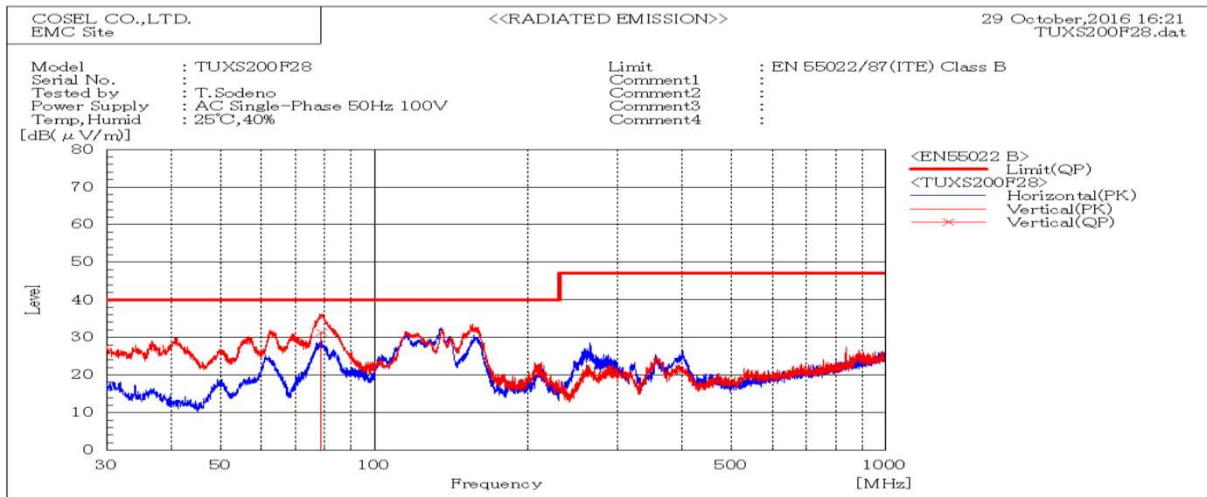


DATA SHEET		Date	31-Oct-16
Model	TUXS200F28	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sodeno



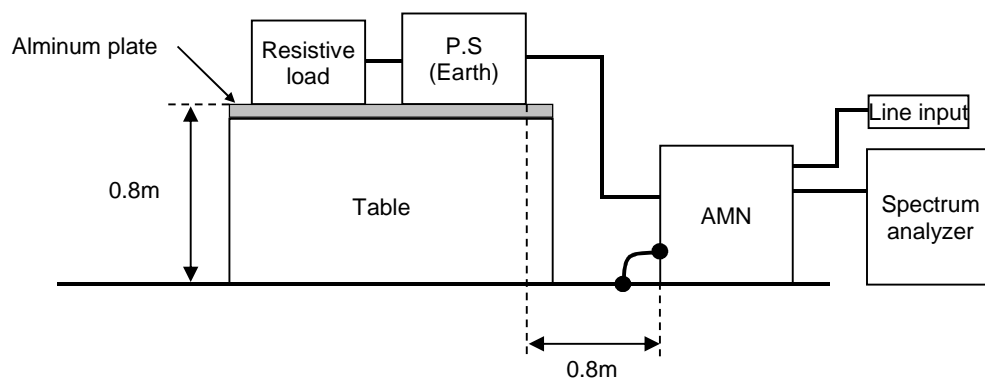
Frequency MHz	Line Phase	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail
		QP	AV	QP	AV	QP	AV	
0.15958	VB	34.6	29.7	65.5	55.5	30.9	25.8	Pass
0.17144	VA	44.3	35.2	64.9	54.9	20.6	19.7	Pass
0.78124	VA	31.4	27	56	46	24.6	19	Pass
0.78283	VB	33.4	28.1	56	46	22.6	17.9	Pass



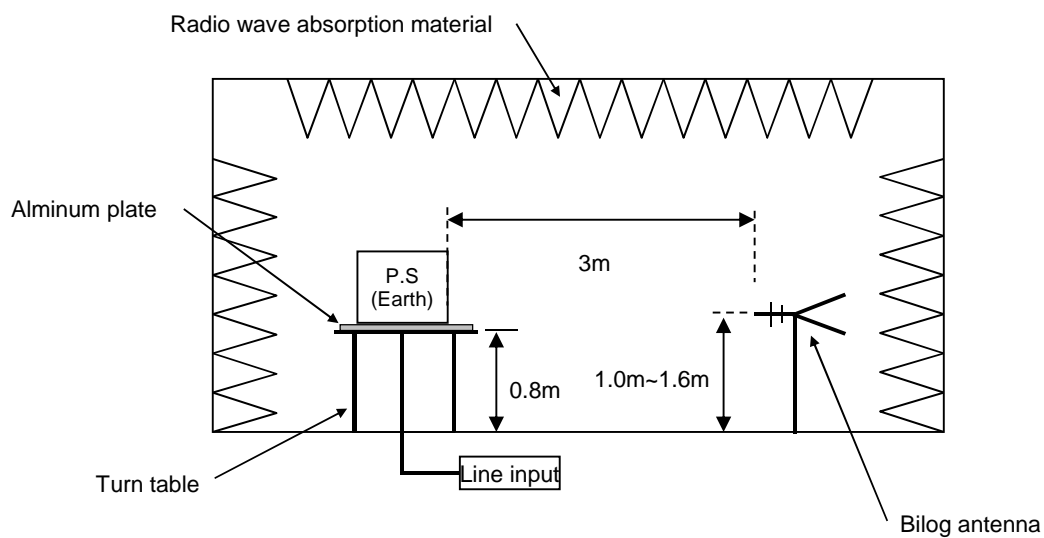
Frequency MHz	Polarization	Stability	Reading dB(μV)	Limit dB(μV/m)	Margin dB(μV/m)	Pass/Fail	Height cm	Angle deg
			QP	QP	QP			
78.685	V	Stable	31.4	40.0	8.6	Pass	115	264

DATA SHEET		Date	31-Oct-16
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sodeno

1. Line conduction



2. Radiated emission



Test: EMI

Model Name:TUXS200F28

○ Photographs of Test Set-Up

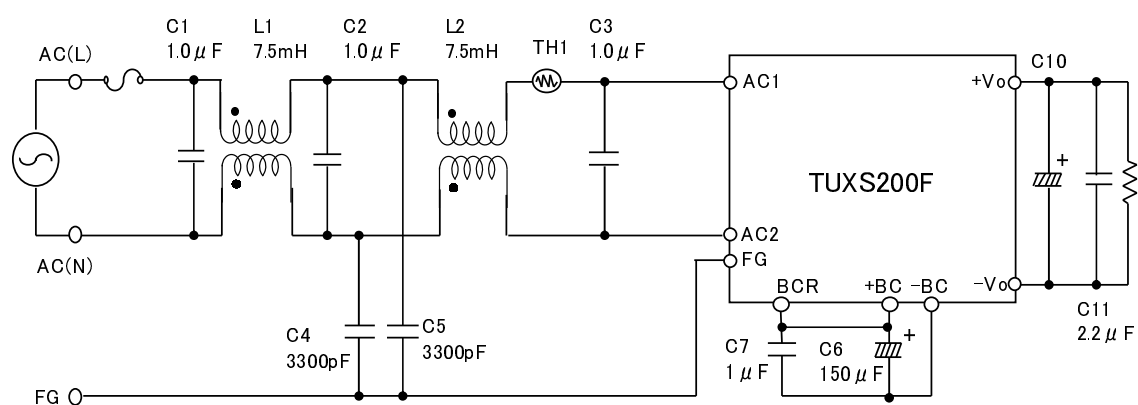
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



- L1,L2 : SCR22-060-1R0A075JH(NEC TOKIN)
- TH1 : 12D2-11LC(SEMITEC)
- C1,C2,C3 : LE105-MX(OKAYA)
- C4,C5 : DE1E3KX332M(MURATA)
- C6 : EKXJ421ELL151MM50S(Nippon Chemi-con)
- C7 : AFS450V105K(OKAYA)
- C10 : PCR1H181MCL1GS(NICHICON) × 3
- C11 : GRM31CR72A225K(MURATA)